Philips Semiconductors-Signetics

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Status	Product Specification
FAST Products	

FAST 74F563, 74F564 Latch/Flip-Flop

74F563 Octal Transparent Latch (3-State)
74F564 Octal D Flip-Flop (3-State)

TYPE	TYPICAL PROPAGATION DELAY	TYPICAL SUPPLY CURRENT (TOTAL)
74F563	5.0ns	40mA

TYPE	TYPICAL f_{MAX}	TYPICAL SUPPLY CURRENT (TOTAL)
74F564	180MHz	50mA

FEATURES

- **74F563 is broadside pinout version of 74F533**
- **74F564 is broadside pinout version of 74F534**
- **Inputs and Outputs on opposite side of package allow easy interface to Microprocessors**
- **Useful as an Input or Output port for Microprocessors**
- **3-State Outputs for Bus Interfacing**
- **Common Output Enable**
- **74F573 and 74F574 are non-inverting versions of 74F563 and 74F564 respectively**
- **These are High-Speed replacements for N8TS807 and N8TS808**

ORDERING INFORMATION

PACKAGES	COMMERCIAL RANGE V_{CC} = 5V±10%; T_A = 0°C to +70°C
20-Pin Plastic DIP	N74F563N, N74F564N
20-Pin Plastic SOL	N74F563D, N74F564D

INPUT AND OUTPUT LOADING AND FAN-OUT TABLE

PINS	DESCRIPTION	74F(U.L.) HIGH/LOW	LOAD VALUE HIGH/LOW
D_0 - D_7	Data inputs	1.0/1.0	20µA/0.6mA
E ('F563)	Latch Enable input (active High)	1.0/1.0	20µA/0.6mA
$\overline{OE}$	Output Enable input (active Low)	1.0/1.0	20µA/0.6mA
CP ('F564)	Clock Pulse input (active rising edge)	1.0/1.0	20µA/0.6mA
$\overline{O}_0$ - $\overline{O}_7$	3-State outputs	150/40	3.0mA/24mA

NOTE:
One (1.0) FAST Unit load is defined as: 20µA in the High state and 0.6mA in the Low state.

DESCRIPTION

The 74F563 is an octal transparent latch coupled to eight 3-State output buffers. The two sections of the device are controlled independently by Enable (E) and Output Enable ($\overline{OE}$) control gates.
The 74F563 is functionally identical to the 74F533 but has a broadside pinout configuration to facilitate PC board layout and allows easy interface with microprocessors.

The data on the D inputs is transferred to the latch outputs when the Enable (E) input is High. The latch remains transparent to the data input while E is High and stores the data that is present one set-up time before the High-to-Low enable transition.

The 3-State output buffers are designed to drive heavily loaded 3-State buses, MOS memories, or MOS microprocessors. The active Low Output Enable ($\overline{OE}$) controls all eight 3-State buffers independently of the latch operation. When $\overline{OE}$ is Low, the latched or transparent data appears at the outputs. When $\overline{OE}$ is High, the outputs are in high impedance "off" state, which means they will neither drive nor load the bus.

The 74F564 is functionally identical to the 74F534 but has a broadside pinout configuration to facilitate PC board layout and allows easy interface with microprocessors.

It is an 8-bit, edge triggered register coupled to eight 3-State output buffers. The two sections of the device are controlled independently by the clock (CP) and Output Enable ($\overline{OE}$) control gates.

The register is fully edge triggered. The state of each D input, one set-up time before the Low-to-High clock transition is transferred to the corresponding flip-flop's $\overline{Q}$ output.

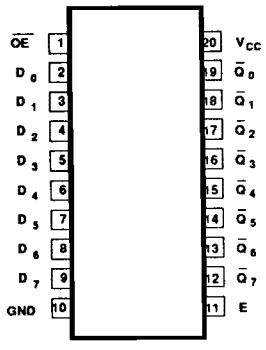
The 3-State output buffers are designed to drive heavily loaded 3-State buses, MOS memories, or MOS microprocessors. The active Low Output Enable ($\overline{OE}$) controls all eight 3-State buffers independently of the register operation. When $\overline{OE}$ is Low, data in the register appears at the outputs. When $\overline{OE}$ is High, the outputs are in high impedance "off" state, which means they will neither drive nor load the bus.

Latch/Flip-Flop

FAST 74F563, 74F564

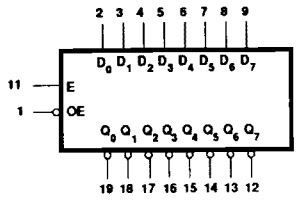
PIN CONFIGURATION

74F563



LOGIC SYMBOL

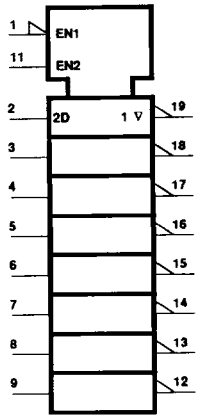
74F563



V_{CC} = Pin 20
GND = Pin 10

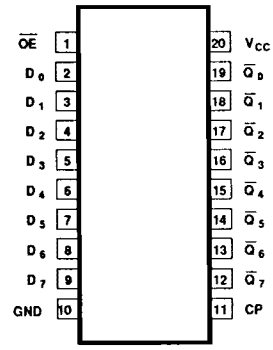
LOGIC SYMBOL(IEEE/IEC)

74F563



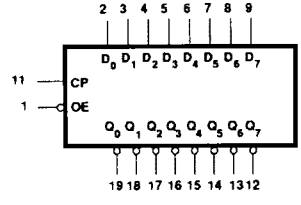
PIN CONFIGURATION

74F564



LOGIC SYMBOL

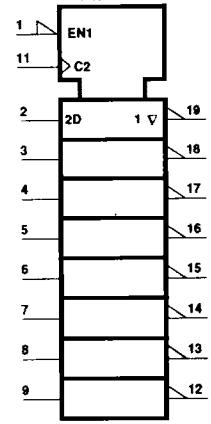
74F564



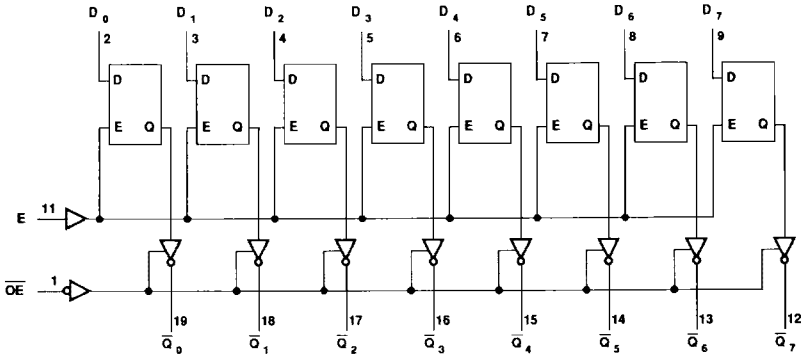
V_{CC} = Pin 20
GND = Pin 10

LOGIC SYMBOL(IEEE/IEC)

74F564

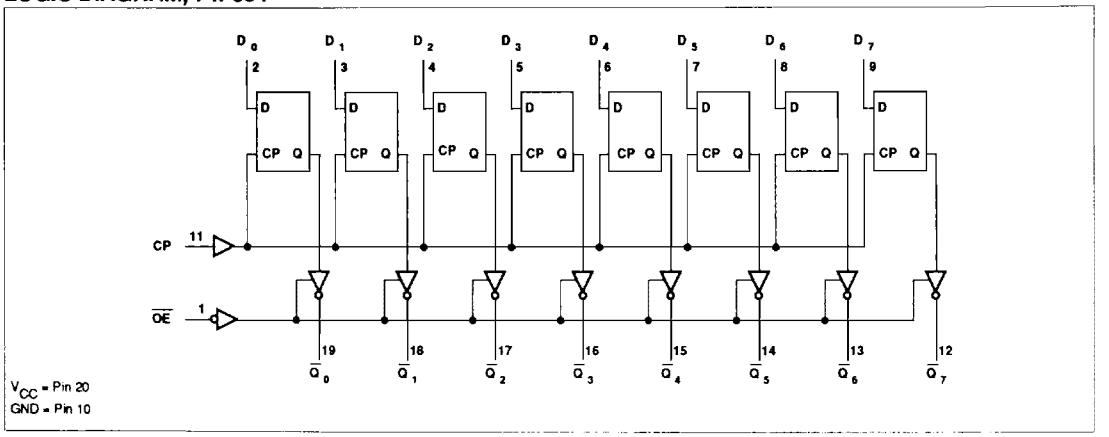


LOGIC DIAGRAM, 74F563



V_{CC} = Pin 20
GND = Pin 10

LOGIC DIAGRAM, 74F564



FUNCTION TABLE, 74F563

INPUTS			INTERNAL REGISTER	OUTPUTS	OPERATING MODE
$\overline{OE}$	E	D_n		$\overline{Q}_0$ - $\overline{Q}_7$	
L	H	L	L	H	Enable and read register
L	H	H	H	L	
L	↓	l	L	H	Latch and read register
L	↓	h	H	L	
L	L	X	NC	NC	Hold
H	L	X	NC	Z	Disable outputs
H	H	D_n	D_n	Z	

H = High voltage level
h = High voltage level one set-up time prior to the High-to-Low E transition
L = Low voltage level
l = Low voltage level one set-up time prior to the High-to-Low E transition
NC = No change
X = Don't care
Z = High impedance "off" state
↓ = High-to-Low E transition

FUNCTION TABLE, 74F564

INPUTS			INTERNAL REGISTER	OUTPUTS	OPERATING MODE
$\overline{OE}$	CP	D_n		$\overline{Q}_0$ - $\overline{Q}_7$	
L	↑	l	L	H	Load and read register
L	↑	h	H	L	
L	↑	X	NC	NC	Hold
H	↑	X	NC	Z	Disable outputs
H	↑	D_n	D_n	Z	

H = High voltage level
h = High voltage level one set-up time prior to the Low-to-High clock transition
L = Low voltage level
l = Low voltage level one set-up time prior to the Low-to-High clock transition
NC = No change
X = Don't care
Z = High impedance "off" state
↑ = Low-to-High clock transition
↑ = Not a Low-to-High clock transition

ABSOLUTE MAXIMUM RATINGS

(Operation beyond the limits set forth in this table may impair the useful life of the device. Unless otherwise noted these limits are over the operating free-air temperature range.)

SYMBOL	PARAMETER	RATING	UNIT
V_{CC}	Supply voltage	-0.5 to +7.0	V
V_{IN}	Input voltage	-0.5 to +7.0	V
I_{IN}	Input current	-30 to +5	mA
V_{OUT}	Voltage applied to output in High output state	-0.5 to +V_{CC}	V
I_{OUT}	Current applied to output in Low output state	48	mA
T_A	Operating free-air temperature range	0 to +70	°C
T_{STG}	Storage temperature	-65 to +150	°C

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	LIMITS			UNIT
		Min	Nom	Max	
V_{CC}	Supply voltage	4.5	5.0	5.5	V
V_{IH}	High-level input voltage	2.0			V
V_{IL}	Low-level input voltage			0.8	V
I_{IK}	Input clamp current			-18	mA
I_{OH}	High-level output current			-3	mA
I_{OL}	Low-level output current			24	mA
T_A	Operating free-air temperature range	0		70	°C

DC ELECTRICAL CHARACTERISTICS (Over recommended operating free-air temperature range unless otherwise noted.)

SYMBOL	PARAMETER			TEST CONDITIONS[1]		LIMITS			UNIT
						Min	Typ[2]	Max	
V_{OH}	High-level output voltage			V_{CC} = MIN, V_{IL} = MAX, V_{IH} = MIN, I_{OH} = MAX	±10%V_{CC}	2.4			V
					±5%V_{CC}	2.7	3.4		V
V_{OL}	Low-level output voltage			V_{CC} = MIN, V_{IL} = MAX, V_{IH} = MIN, I_{OL} = MAX	±10%V_{CC}		0.35	0.50	V
					±5%V_{CC}		0.35	0.50	V
V_{IK}	Input clamp voltage			V_{CC} = MIN, I_I = I_{IK}			-0.73	-1.2	V
I_I	Input current at maximum input voltage			V_{CC} =MAX, V_I = 7.0V				100	µA
I_{IH}	High-level input current			V_{CC} = MAX, V_I = 2.7V				20	µA
I_{IL}	Low-level input current			V_{CC} = MAX, V_I = 0.5V				-0.6	mA
I_{OZH}	Off state output current, High-level voltage applied			V_{CC} = MAX, V_O = 2.7V				50	µA
I_{OZL}	Off state output current, Low-level voltage applied			V_{CC} = MAX, V_O = 0.5V				-50	µA
I_{OS}	Short circuit output current[3]			V_{CC} = MAX		-60		-150	mA
I_{CC}	Supply current (total)	I_{CCH}	74F563	V_{CC} = MAX			30	45	mA
		I_{CCL}					40	60	mA
		I_{CCZ}					45	65	mA
		I_{CCH}	74F564	V_{CC} = MAX			45	65	mA
		I_{CCL}					50	75	mA
		I_{CCZ}					55	80	mA

NOTES:

1. For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type.
2. All typical values are at V_{CC} = 5V, T_A = 25°C.
3. Not more than one output should be shorted at a time. For testing I_{OS}, the use of high-speed test apparatus and/or sample-and-hold techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise, prolonged shorting of a High output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests, I_{OS} tests should be performed last.

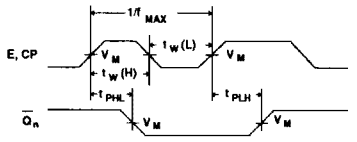
AC ELECTRICAL CHARACTERISTICS

SYMBOL	PARAMETER		TEST CONDITION	LIMITS					UNIT
				T_A = +25°C, V_{CC} = 5V, C_L = 50pF, R_L = 500Ω			T_A = 0°C to +70°C, V_{CC} = 5V ±10%, C_L = 50pF, R_L = 500Ω		
				Min	Typ	Max	Min	Max	
t_{PLH} t_{PHL}	Propagation delay D_n to $\overline{Q}_n$	74F563	Waveform 2	4.0 2.5	5.5 4.0	8.5 6.5	3.5 2.0	9.5 7.0	ns
t_{PLH} t_{PHL}	Propagation delay E to $\overline{Q}_n$		Waveform 1	5.0 3.0	6.5 5.0	9.5 7.0	4.5 3.0	10.5 7.0	ns
t_{PZH} t_{PZL}	Output Enable time to High or Low level		Waveform 4 Waveform 5	2.5 4.0	4.5 6.0	7.5 8.0	2.5 3.5	8.5 8,5	ns
t_{PHZ} t_{PLZ}	Output Disable time to High or Low level		Waveform 4 Waveform 5	1.5 1.5	3.0 3.0	6.0 5.5	1.0 1.0	7.0 6.0	ns
f_{MAX}	Maximum Clock frequency	74F564	Waveform 1	160	180		150		MHz
t_{PLH} t_{PHL}	Propagation delay CP to $\overline{Q}_n$		Waveform 1	3.5 3.5	5.0 5.0	8.0 8.0	3.0 3.0	8.5 8.5	ns
t_{PZH} t_{PZL}	Output Enable time to High or Low level		Waveform 4 Waveform 5	2.5 4.0	4.5 5.5	7.5 8.0	2.0 3.5	8.0 8.5	ns
t_{PHZ} t_{PLZ}	Output Disable time to High or Low level		Waveform 4 Waveform 5	1.0 1.0	3.0 2.5	6.0 5.5	1.0 1.0	7.0 6.0	ns

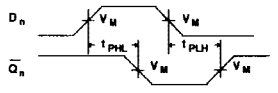
AC SETUP REQUIREMENTS

SYMBOL	PARAMETER		TEST CONDITION	LIMITS					UNIT
				T_A = +25°C, V_{CC} = 5V, C_L = 50pF, R_L = 500Ω			T_A = 0°C to +70°C, V_{CC} = 5V ±10%, C_L = 50pF, R_L = 500Ω		
				Min	Typ	Max	Min	Max	
$t_s(H)$ $t_s(L)$	Set-up time D_n to E	74F563	Waveform 3	1.0 1.0			1.0 1.0		ns
$t_h(H)$ $t_h(L)$	Hold time D_n to E		Waveform 3	3.0 2.5			3.0 2.5		ns
$t_w(H)$	E Pulse width, High		Waveform 1	3.5			3.5		ns
$t_s(H)$ $t_s(L)$	Set-up time D_n to CP	74F564	Waveform 3	2.0 2.0			2.0 2.5		ns
$t_h(H)$ $t_h(L)$	Hold time D_n to CP		Waveform 3	1.0 1.0			1.5 1.5		ns
$t_w(H)$ $t_w(L)$	CP Pulse width, High or Low		Waveform 1	3.5 3.5			3.5 3.5		ns

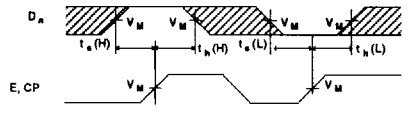
AC WAVEFORMS



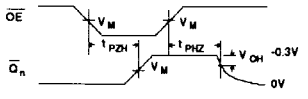
Waveform 1. Propagation Delay, Clock And Enable Inputs To Output, Enable, and Clock Pulse Widths, and Maximum Clock Frequency



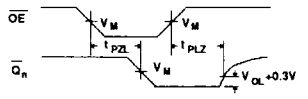
Waveform 2. Propagation Delay For Data To Outputs



Waveform 3. Data Setup And Hold Times



Waveform 4. 3-State Output Enable Time To High Level And Output Disable Time From High Level

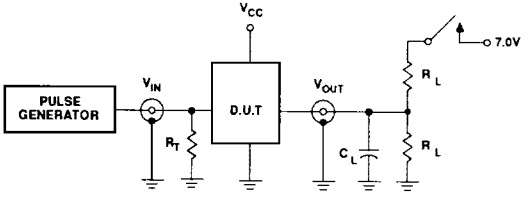


Waveform 5. 3-State Output Enable Time To Low Level And Output Disable Time From Low Level

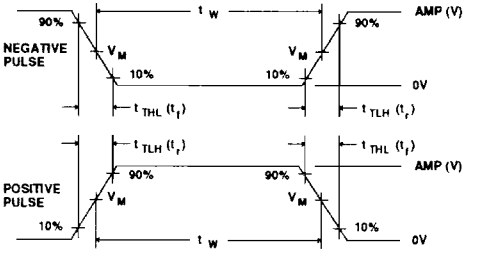
NOTE: For all waveforms, V_M = 1.5V.

The shaded areas indicate when the input is permitted to change for predictable output performance.

TEST CIRCUIT AND WAVEFORMS



Test Circuit For 3-State Outputs



V_M = 1.5V

Input Pulse Definition

SWITCH POSITION

TEST	SWITCH
t_{PLZ}	closed
t_{PZL}	closed
All other	open

DEFINITIONS

R_L = Load resistor; see AC CHARACTERISTICS for value.

C_L = Load capacitance includes jig and probe capacitance; see AC CHARACTERISTICS for value.

R_T = Termination resistance should be equal to Z_{OUT} of pulse generators.

FAMILY	INPUT PULSE REQUIREMENTS				
	Amplitude	Rep. Rate	t_W	t_{TLH}	t_{THL}
74F	3.0V	1MHz	500ns	2.5ns	2.5ns